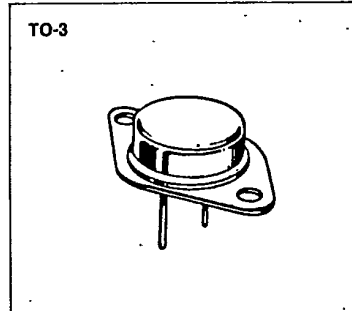
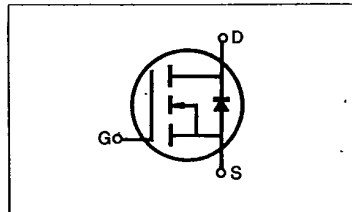


**IRF130/131/132/133****N-CHANNEL  
POWER MOSFETS****FEATURES**

- Low  $R_{DS(on)}$
- Improved inductive ruggedness
- Fast switching times
- Rugged polysilicon gate cell structure
- Low input capacitance
- Extended safe operating area
- Improved high temperature reliability
- TO-3 package (Standard)

**PRODUCT SUMMARY**

Part Number	V <sub>DS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
IRF130	100V	0.18Ω	14A
IRF131	60V	0.18Ω	14A
IRF132	100V	0.25Ω	12A
IRF133	60V	0.25Ω	12A

**MAXIMUM RATINGS**

Characteristic	Symbol	IRF130	IRF131	IRF132	IRF133	Unit
Drain-Source Voltage (1)	V <sub>DSS</sub>	100	60	100	60	Vdc
Drain-Gate Voltage (R <sub>GS</sub> =1.0MΩ) (1)	V <sub>DGR</sub>	100	60	100	60	Vdc
Gate-Source Voltage	V <sub>GS</sub>	±20				Vdc
Continuous Drain Current T <sub>C</sub> =25°C	I <sub>D</sub>	14	14	12	12	Adc
Continuous Drain Current T <sub>C</sub> =100°C	I <sub>D</sub>	9.0	9.0	8.0	8.0	Adc
Drain Current—Pulsed (3)	I <sub>DM</sub>	56	56	48	48	Adc
Gate Current—Pulsed	I <sub>GM</sub>	±1.5				Adc
Total Power Dissipation @ T <sub>C</sub> =25°C Derate above 25°C	P <sub>D</sub>	75 0.6				Watts W/°C
Operating and Storage Junction Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150				°C
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	T <sub>L</sub>	300				°C

Notes: (1) T<sub>J</sub>=25°C to 150°C

(2) Pulse test: Pulse width≤300μs, Duty Cycle≤2%

(3) Repetitive rating: Pulse width limited by max. junction temperature

## IRF130/131/132/133

N-CHANNEL  
POWER MOSFETSELECTRICAL CHARACTERISTICS (T<sub>C</sub>=25°C unless otherwise specified)

Characteristic	Symbol	Type	Min	Typ	Max	Units	Test Conditions
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	IRF130 IRF132	100	—	—	V	V <sub>GS</sub> =0V
		IRF131 IRF133	60	—	—	V	I <sub>D</sub> =250μA
Gate Threshold Voltage	V <sub>GS(th)</sub>	ALL	2.0	—	4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA
Gate-Source Leakage Forward	I <sub>GSS</sub>	ALL	—	—	100	nA	V <sub>GS</sub> =20V
Gate-Source Leakage Reverse	I <sub>GSS</sub>	ALL	—	—	-100	nA	V <sub>GS</sub> =-20V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	ALL	—	—	250	μA	V <sub>DS</sub> =Max. Rating, V <sub>GS</sub> =0V
		—	—	—	1000	μA	V <sub>DS</sub> =Max. Rating×0.8, V <sub>GS</sub> =0V, T <sub>C</sub> =125°C
On-State Drain-Source Current (2)	I <sub>D(on)</sub>	IRF130 IRF131	14	—	—	A	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on) max.</sub> , V <sub>GS</sub> =10V
		IRF132 IRF133	12	—	—	A	
Static Drain-Source On-State Resistance (2)	R <sub>DS(on)</sub>	IRF130 IRF131	—	0.10	0.18	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =8.0A
		IRF132 IRF133	—	0.20	0.25	Ω	
Forward Transconductance (2)	g <sub>fs</sub>	ALL	4.0	5.5	—	S	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on) max.</sub> , I <sub>D</sub> =8.0A
Input Capacitance	C <sub>iss</sub>	ALL	—	680	800	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, f=1.0MHz
Output Capacitance	C <sub>oss</sub>	ALL	—	300	500	pF	
Reverse Transfer Capacitance	C <sub>ras</sub>	ALL	—	100	150	pF	
Turn-On Delay Time	t <sub>d(on)</sub>	ALL	—	—	30	ns	V <sub>DD</sub> =0.5BV <sub>DSS</sub> , I <sub>D</sub> =8.0A, Z <sub>O</sub> =15 Ω (MOSFET switching times are essentially independent of operating temperature.)
Rise Time	t <sub>r</sub>	ALL	—	—	75	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	ALL	—	—	40	ns	
Fall Time	t <sub>f</sub>	ALL	—	—	45	ns	
Total Gate Charge (Gate-Source Plus Gate-Drain)	Q <sub>g</sub>	ALL	—	18	30	nC	V <sub>GS</sub> =10V, I <sub>D</sub> =18A, V <sub>DS</sub> =0.8 Max. Rating (Gate charge is essentially independent of operating temperature.)
Gate-Source Charge	Q <sub>gs</sub>	ALL	—	6.0	—	nC	
Gate-Drain ("Miller") Charge	Q <sub>gd</sub>	ALL	—	12.0	—	nC	

## THERMAL RESISTANCE

Junction-to-Case	R <sub>thJC</sub>	ALL	—	—	1.67	K/W	
Case-to-Sink	R <sub>thCS</sub>	ALL	—	0.1	—	K/W	Mounting surface flat, smooth, and greased
Junction-to-Ambient	R <sub>thJA</sub>	ALL	—	—	30	K/W	Free Air Operation

Notes: (1) T<sub>J</sub>=25°C to 150°C

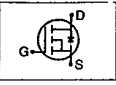
(2) Pulse test: Pulse width≤300μs, Duty Cycle≤2%

(3) Repetitive rating: Pulse width limited by max. junction temperature

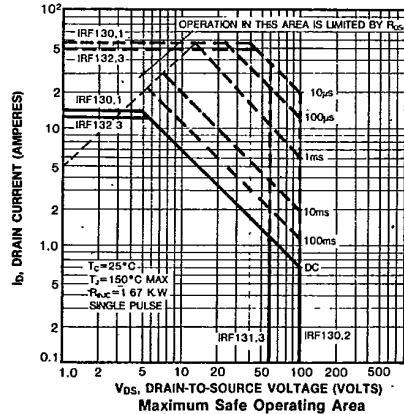
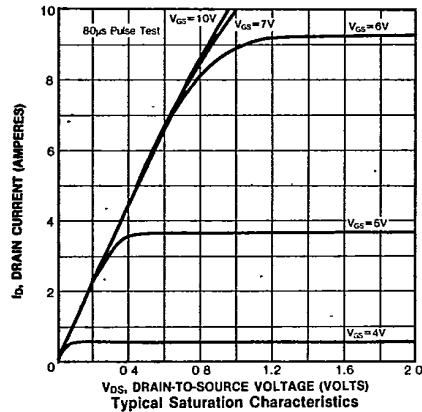
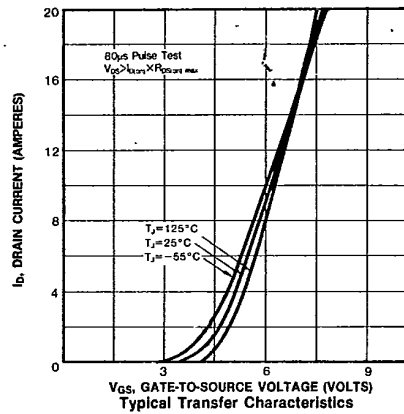
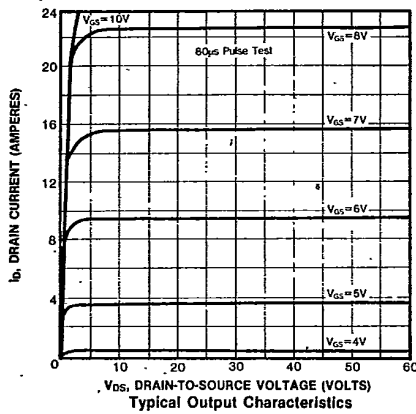
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**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

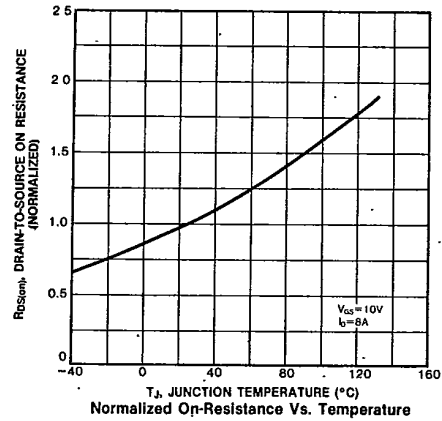
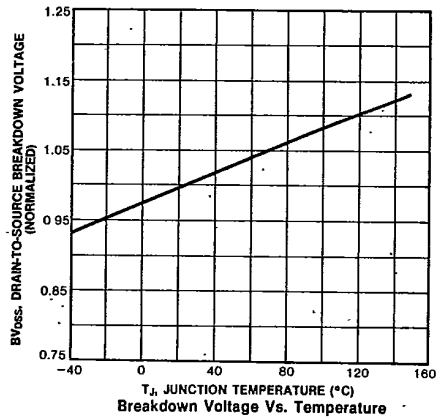
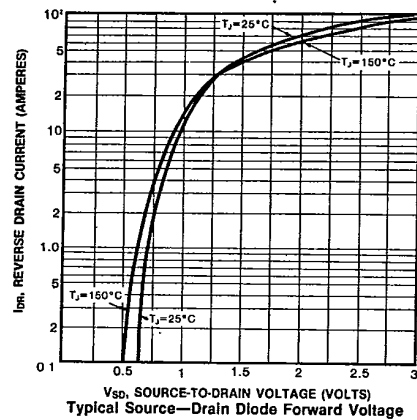
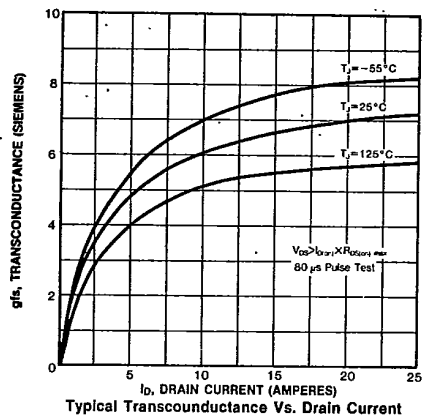
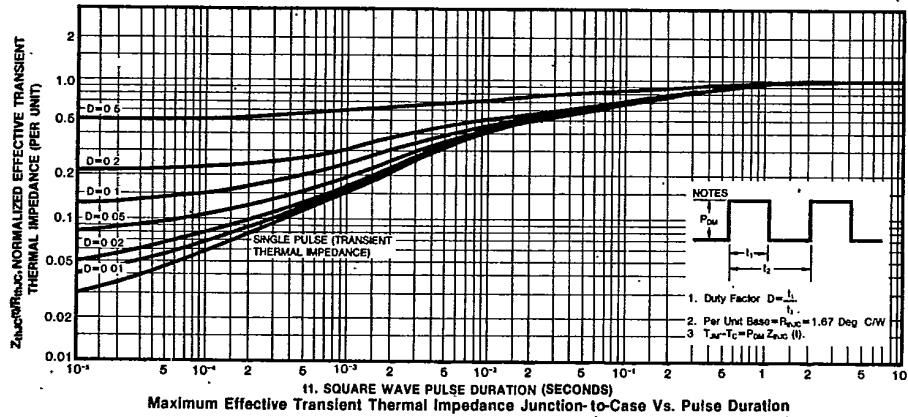
Characteristic	Symbol	Type	Min	Typ	Max	Units	Test Conditions
Continuous Source Current (Body Diode)	I <sub>S</sub>	IRF130 IRF131	—	—	14	A	Modified MOSFET symbol showing the integral reverse P-N junction rectifier 
		IRF132 IRF133	—	—	12	A	
Pulse Source Current (Body Diode) (3)	I <sub>SM</sub>	IRF130 IRF131	—	—	56	A	
		IRF132 IRF133	—	—	48	A	
Diode Forward Voltage (2)	V <sub>SD</sub>	IRF130 IRF131	—	—	2.5	V	T <sub>C</sub> =25°C, I <sub>S</sub> =14A, V <sub>GS</sub> =0V
		IRF132 IRF133	—	—	2.3	V	T <sub>C</sub> =25°C, I <sub>S</sub> =12A, V <sub>GS</sub> =0V
Reverse Recovery Time	t <sub>rr</sub>	ALL	—	360	—	ns	T <sub>J</sub> =150°C, I <sub>F</sub> =14A, dI <sub>F</sub> /dt=100A/μs

Notes: (1) T<sub>J</sub>=25°C to 150°C (2) Pulse test: Pulse width ≤ 300μs, Duty Cycle ≤ 2%  
(3) Repetitive rating: Pulse width limited by max. junction temperature



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